

PRODUCT TECHNICAL BRIEF

KYKY EM-8000 Field-Emission Scanning Electron Microscope

KYKY EM-8000 Field-Emission Scanning Electron Microscope - LeakLab solutions for leak testing, vacuum systems and test equipment.

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Technical and Project Information

Schottky field-emission SEM platform introduced by KYKY for high-resolution materials imaging. Current availability, detector package, low-vacuum capability, guaranteed resolution and analytical options must be confirmed by manufacturer quotation.

The EM-8000 is a Schottky field-emission SEM platform for high-resolution surface imaging and microanalysis. KYKY's product history identifies the model as a 2014-generation instrument with approximately 1.5 nm resolution.

Configurable scope

- Secondary-electron and backscattered-electron imaging
- High-vacuum and, where supported by the exact version, low-vacuum operation
- Motorized specimen stage and automated electron-optical alignment
- Optional EDS, EBSD, cathodoluminescence or WDS analysis

The former page described multiple modifications without a current manufacturer configuration table. Treat the EM-8000 as a legacy or quotation-controlled platform: verify source type, resolution at each voltage, chamber size, stage travel, detector ports, pumps, utilities, software and service status before procurement.

Installation, user training, dimensional calibration and acceptance testing should be specified as separate deliverables for the destination laboratory.

- Helium Reference Leaks
- Scanning Electron Microscopes
- Leak-Detector Accessories

WORLDWIDE PROJECT CONTACT

Send the test object or system, operating conditions, target sensitivity or pressure range, applicable standard, destination country, quantity and schedule. LeakLab will review the project scope.

mail@leaklab.org

Regarding: KYKY EM-8000 Field-Emission Scanning Electron Microscope

Specifications, standards, verification scope, availability and commercial terms must be confirmed for the exact configuration and destination jurisdiction before order or project acceptance.